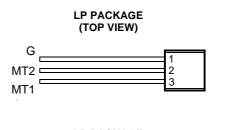
- 1.5 A RMS
- Glass Passivated Wafer
- 400 V to 600 V Off-State Voltage
- Max I<sub>GT</sub> of 10 mA
- Package Options

PACKAGE	PACKING	PART # SUFFIX		
LP	Bulk	(None)		
LP with fomed leads	Tape and Reel	R		



MDC2AA

LP PACKAGE WITH FORMED LEADS (TOP VIEW)



MDC2AB

#### absolute maximum ratings over operating case temperature (unless otherwise noted)

RATING			VALUE	UNIT	
Repetitive peak off-state voltage (see Note 1)	TICP206D TICP206M	V <sub>DRM</sub>	400 600	V	
Full-cycle RMS on-state current at (or below) 85°C case temperature (see Note 2)			1.5	А	
Peak on-state surge current full-sine-wave (see Note 3)			10	А	
Peak on-state surge current half-sine-wave (see Note 4)			12	А	
Peak gate current			±0.2	А	
Average gate power dissipation at (or below) 85°C case temperature (see Note 5)			0.3	W	
Operating case temperature range			-40 to +110	°C	
Storage temperature range			-40 to +125	°C	
Lead temperature 1.6 mm from case for 10 seconds			230	°C	

NOTES: 1. These values apply bidirectionally for any value of resistance between the gate and Main Terminal 1.

 This value applies for 50-Hz full-sine-wave operation with resistive load. Above 85°C derate linearly to 110°C case temperature at the rate of 60 mA/°C.

3. This value applies for one 50-Hz full-sine-wave when the device is operating at (or below) the rated value of on-state current. Surge may be repeated after the device has returned to original thermal equilibrium. During the surge, gate control may be lost.

- 4. This value applies for one 50-Hz half-sine-wave when the device is operating at (or below) the rated value of on-state current. Surge may be repeated after the device has returned to original thermal equilibrium. During the surge, gate control may be lost.
- 5. This value applies for a maximum averaging time of 20 ms.

#### electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	ТҮР	МАХ	UNIT
I <sub>DRM</sub>	Repetitive peak off- state current	$V_D$ = rated $V_{DRM}$	$I_{\rm G}=0$				±20	μΑ
I <sub>GTM</sub>		V <sub>supply</sub> = +12 V†	$R_L = 10 \Omega$	t <sub>p(g)</sub> > 20 μs			8	mA
	Peak gate trigger	$V_{supply} = +12 V^{\dagger}$	$R_L = 10 \ \Omega$	t <sub>p(g)</sub> > 20 μs			-8	
	current	$V_{supply} = -12 V^{\dagger}$	$R_L = 10 \ \Omega$	t <sub>p(g)</sub> > 20 μs			-8	
		$V_{supply} = -12 V^{\dagger}$	$R_L = 10 \ \Omega$	t <sub>p(g)</sub> > 20 μs			10	
V <sub>GTM</sub>		$V_{supply} = +12 V^{\dagger}$	$R_L = 10 \Omega$	t <sub>p(g)</sub> > 20 μs			2.5	v
	Peak gate trigger	V <sub>supply</sub> = +12 V†	$R_L = 10 \Omega$	t <sub>p(g)</sub> > 20 μs			-2.5	
	voltage	$V_{supply} = -12 V^{\dagger}$	$R_L = 10 \ \Omega$	t <sub>p(g)</sub> > 20 μs			-2.5	
		$V_{supply} = -12 V^{\dagger}$	$R_L = 10 \ \Omega$	t <sub>p(g)</sub> > 20 μs			2.5	

† All voltages are with respect to Main Terminal 1.

### PRODUCT INFORMATION

Information is current as of publication date. Products conform to specifications in accordance with the terms of Power Innovations standard warranty. Production processing does not necessarily include testing of all parameters.



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#### electrical characteristics at 25°C case temperature (unless otherwise noted) (continued)

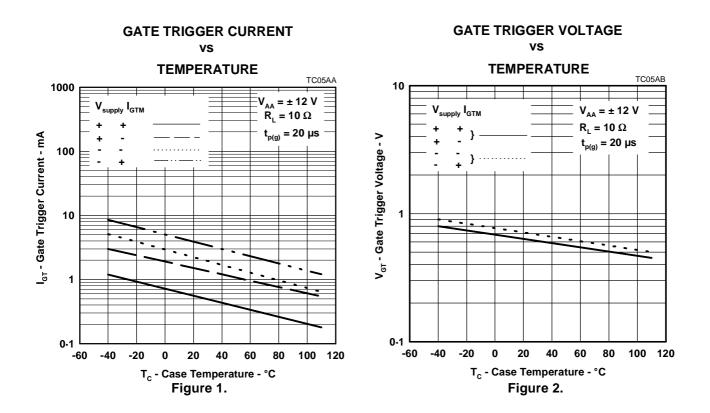
PARAMETER TEST CONDITIONS			ONS	MIN	ТҮР	МАХ	UNIT	
V <sub>TM</sub>	Peak on-state voltage	$I_{TM} = \pm 1 A$	I <sub>G</sub> = 50 mA	(see Note 6)			±2.2	V
Ι <sub>Η</sub>	Holding current	$V_{supply} = +12 V^{+}$ $V_{supply} = -12 V^{+}$	$I_{G} = 0$ $I_{G} = 0$	Init' I <sub>TM</sub> = 100 mA Init' I <sub>TM</sub> = -100 mA			30 -30	mA
١ <sub>L</sub>	Latching current	V <sub>supply</sub> = +12 V† V <sub>supply</sub> = -12 V†	(see Note 7)				40 -40	mA

† All voltages are with respect to Main Terminal 1.

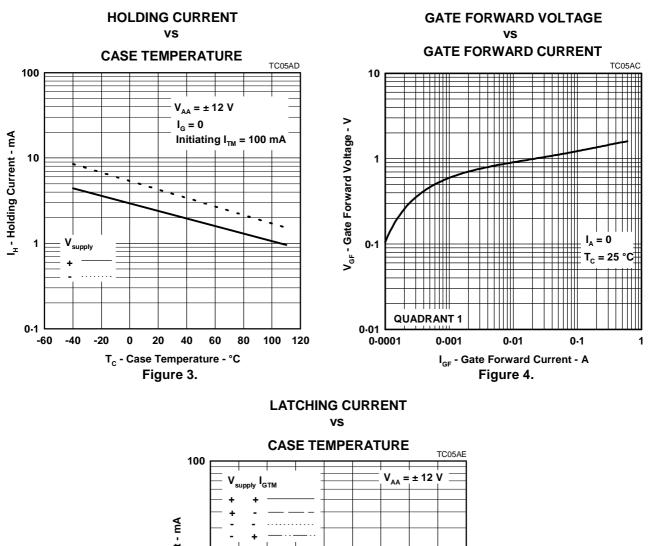
NOTES: 6. This parameter must be measured using pulse techniques, t<sub>p</sub> = ≤ 1 ms, duty cycle ≤ 2 %. Voltage-sensing contacts separate from the current carrying contacts are located within 3.2 mm from the device body.

7. The triacs are triggered by a 15-V (open circuit amplitude) pulse supplied by a generator with the following characteristics:  $R_G = 100 \Omega$ ,  $t_{p(g)} = 20 \mu s$ ,  $t_r = \le 15 ns$ , f = 1 kHz.

#### **TYPICAL CHARACTERISTICS**



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#### **TYPICAL CHARACTERISTICS**

I<sub>L</sub> - Latching Current - mA 10 • • 1 -60 -40 -20 0 20 40 80 100 120 60 T<sub>c</sub> - Case Temperature - °C Figure 5.



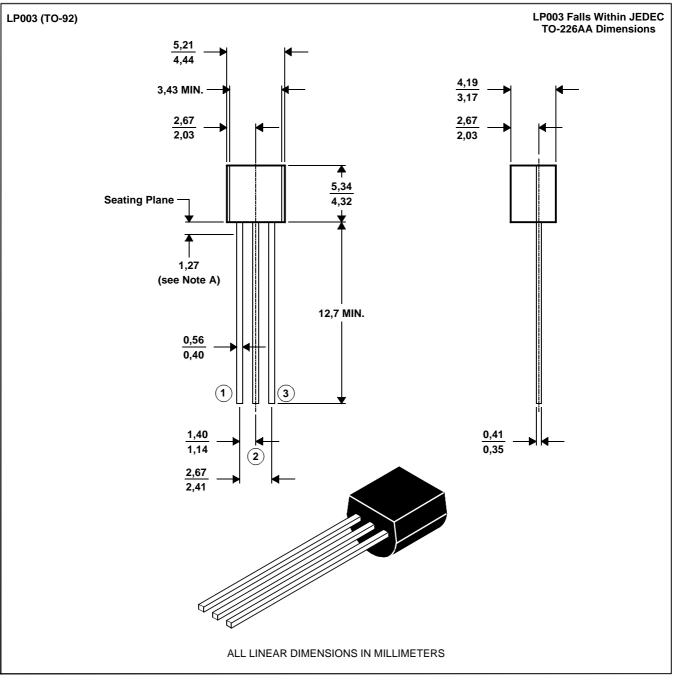
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#### **MECHANICAL DATA**

## LP003 (TO-92)

#### 3-pin cylindical plastic package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



NOTE A: Lead dimensions are not controlled in this area.

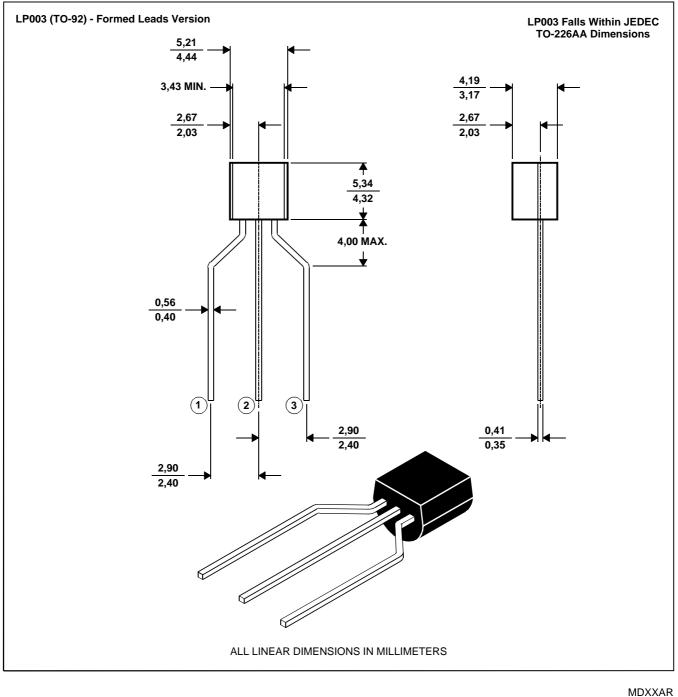
MDXXAX

#### **MECHANICAL DATA**

#### LP003 (TO-92)

#### 3-pin cylindical plastic package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



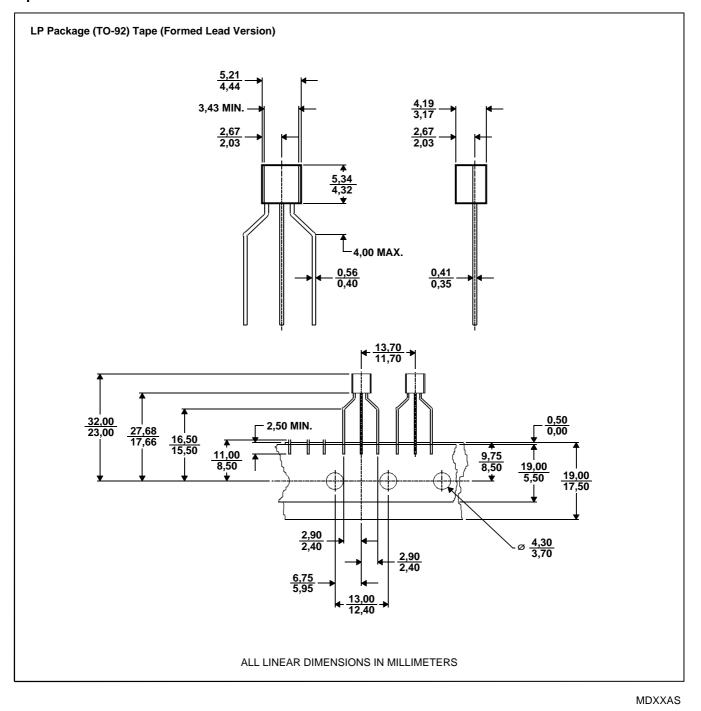


#### INFORMATION PRODUCT

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#### **MECHANICAL DATA**

# LPR tape dimensions



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